


<b>Search Notes</b>  	<b>Application/Control No.</b>  10551896	<b>Applicant(s)/Patent Under Reexamination</b>  BEYER ET AL.
	<b>Examiner</b>  MEHMOOD B KHAN	<b>Art Unit</b>  2617

SEARCHED			
Class	Subclass	Date	Examiner
455	436-453	12/20/2008	MBK

SEARCH NOTES		
Search Notes	Date	Examiner
keyword searched above class/subclasses - see attached search history	12/20/2008	MBK
search updated	6/29/2009	MBK

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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